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ICS 31.08
CCS L 53

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ/T 2658.8-2015

Replacing SJ/T 2658.8-1986

Measuring method for semiconductor infrared-emitting diode. Part 8: Radiant intensity

半导体红外发射二极管测量方法 第8部分：辐射强度

(English Translation)

Issued on: October 10, 2015 **Implemented on: April 1, 2016**

Issued by: Ministry of Industry and Information Technology

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What this standard covers

This standard specifies the measurement principle, measurement procedure and specified conditions of the radiation intensity of semiconductor infrared emission diodes (hereinafter referred to as devices). This standard applies to semiconductor infrared emitting diodes.

Document data

International classification (ICS): 31.08.

Chinese classification (CCS): L53.

Estimated length of the Chinese original: 5,543 words.

Supersedes the earlier edition SJ/T 2658.8-1986.

Standards quoted by this document

GB/T 2900.65-2004; SJ/T 2658.1; CIE 127-1997

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